

# DUAL 128-BIT MOS Static Shift Register

**MOSTEK**

## FEATURES:

- ☐ Ion-implanted for full TTL/DTL compatibility — no interface circuitry required
- ☐ Single-phase, TTL/DTL compatible clocks
- ☐ Dual 128-bit static shift registers — 256 bits total
- ☐ Dual sections have independent clocks
- ☐ Recirculate logic built in
- ☐ DC to 1 MHz clock rates
- ☐ Low power dissipation — 130 mW
- ☐ 16-pin dual-in-line package

## APPLICATIONS

- ☐ Delay lines
- ☐ Buffer data storage
- ☐ Recycling test data sequencer
- ☐ Digital filtering

## DESCRIPTION

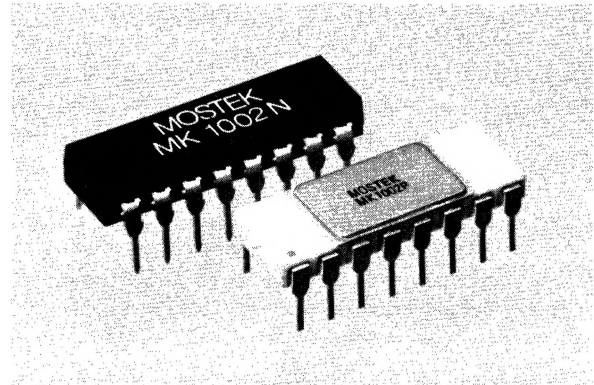
The MK 1002 is a P-channel MOS static shift register utilizing low threshold-voltage processing and ion-implantation to achieve full TTL/DTL compatibility. Each of the two independent 128 bit sections has a built-in clock generator to generate three internal clock phases from a single-phase TTL-level external input. In addition, each section has input logic for loading or recirculating data within the register. (See Functional Diagram.) The positive-logic Boolean expression for this action is:

$$\text{OUT (delayed 128 bits)} = (R_C) (D_{in}) + (\overline{R_C}) (R_{in})$$

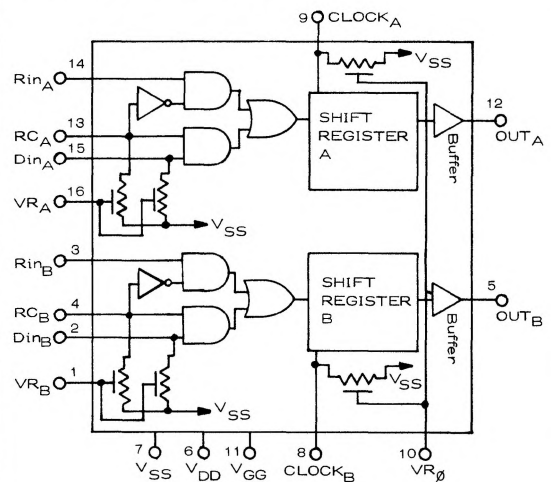
The Data, Recirculate Control, and Clock inputs are provided

with internal pull-up resistors to  $V_{SS}$  (+5V) for use when driving from TTL. These resistors can be disabled when driving from circuitry with larger output-voltage swings, such as DTL. Enabling of pull-up resistors is accomplished by connecting the appropriate terminal to  $V_{GG}$ ; disabling by connecting to  $V_{SS}$ . The Recirculate inputs are not provided with pull-up resistors since they are generally driven from MOS.

Shifting data into the register is accomplished while the Clock input is low. Output data appears following the positive-going Clock edge. Data in each register can be held indefinitely by maintaining the Clock input high.



## FUNCTIONAL DIAGRAM



## OPERATING NOTES

$R_C$	$R_{in}$	$D_{in}$	DATA ENTERED
1	X	1	1
1	X	0	0
0	1	X	1
0	0	X	0

"1" =  $V_{SS} = +5V$

"0" =  $V_{DD} = \text{Grd}$

X = No Effect

Output Logic: See Description.

## ABSOLUTE MAXIMUM RATINGS

Supply Voltage, $V_{DD}$	$V_{SS} - 10.0 \text{ V}$
Supply Voltage, $V_{GG}$	$V_{SS} - 20.0 \text{ V}$
Voltage at any Input or Output	$V_{SS} + 0.3 \text{ V}$ to $V_{SS} - 10.0 \text{ V}$
Operating Free-air Temperature Range	$0^\circ\text{C}$ to $+75^\circ\text{C}$
Storage Temperature Range	$-55^\circ\text{C}$ to $+150^\circ\text{C}$

## RECOMMENDED OPERATING CONDITIONS ( $0^\circ\text{C} \leq T_A \leq 75^\circ\text{C}$ )

		PARAMETER	MIN	TYP	MAX	UNITS	COMMENTS
POWER	$V_{SS}$	Supply Voltage	4.75	5.0	5.25	V	$V_{DD} = 0 \text{ V}$
	$V_{GG}$	Supply Voltage <sup>(1)</sup>	-12.6	-12.0	-11.4	V	
INPUTS	$V_{IL}$	Input Voltage, Logic 0 <sup>(2)</sup>		0	$V_{SS}-4$	V	
	$V_{IH}$	Input Voltage, Logic 1	$V_{SS}-1$	5.0	$V_{SS}$	V	
INPUT TIMING	f	Clock Repetition Rate	DC		1	MHz	See Timing Diagram
	$t_{\phi P}$	Clock Pulse Width	0.35		10	$\mu\text{s}$	
	$t_{\phi d}$	Clock Pulse Delay	0.4			$\mu\text{s}$	
	$t_{\phi r}$	Clock Pulse Risettime	.010		0.2	$\mu\text{s}$	
	$t_{\phi f}$	Clock Pulse Falltime	.010		0.2	$\mu\text{s}$	
	$t_{dld}$	Data Leadtime	50			ns	
	$t_{dlg}$	Data Lagtime	200			ns	
	$t_{rld}$	Recirculate Control Leadtime	100			ns	
	$t_{rlg}$	Recirculate Control Lagtime	300			ns	

## ELECTRICAL CHARACTERISTICS

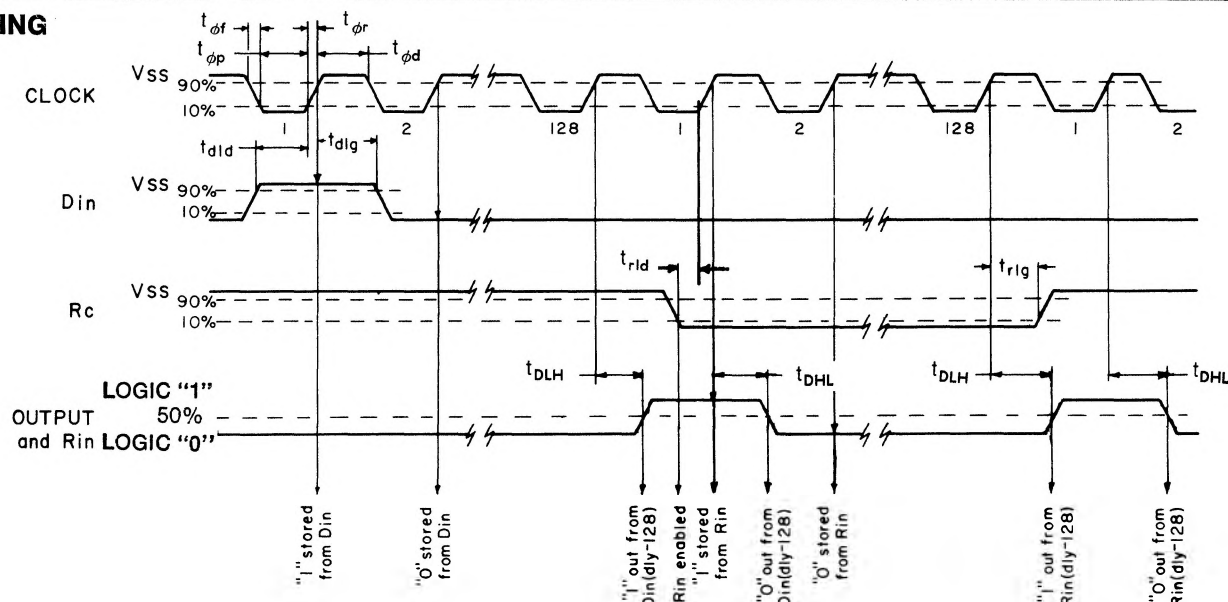
( $V_{SS} = +5 \pm 0.25\text{V}$ ,  $V_{GG} = -12 \pm 0.6\text{V}$ ,  $V_{DD} = 0\text{V}$ ,  $T_A = 0^\circ\text{C}$  to  $+75^\circ\text{C}$ , using test circuit shown, unless otherwise noted.)

		PARAMETER	MIN	TYP <sup>3</sup>	MAX	UNITS	CONDITIONS
POWER	$I_{SS}$	Power Supply Current, $V_{SS}$		14	25	mA	$f_\phi = 1 \text{ MHz}$ Inputs & Outputs open
	$I_{GG}$	Power Supply Current, $V_{GG}$		5	10	mA	
INPUTS	$C_i$	Input Capacitance, any Input		3	10	pF	$V_I = V_{SS}$ , $f = 1 \text{ MHz}$ $T_A = 25^\circ\text{C}$
	$I_{IL}$	Input Current, Logic 0: Resistors Disabled <sup>2</sup> Resistors Enabled <sup>2</sup>	-0.3		-40 -1.6	$\mu\text{A}$ mA	$V_I = V_{SS} - 5\text{V}$ $V_I = +0.4\text{V}$
	$I_{IH}$	Input Current, Logic 1, Any Input			40	$\mu\text{A}$	$VR_A, VR_B, VR_\phi = V_{SS}$ $V_I = V_{SS}$
	$I_{IR(on)}$	Input Current at Recirculate Inputs <sup>2</sup>			-40	$\mu\text{A}$	$VR_A, VR_B, VR_\phi = V_{GG}$ $V_I = V_{SS} - 5\text{V}$
OUTPUTS	$V_{OL}$	Output Voltage, Logic 0 (3)			0.4	V	$I_L = -1.6 \text{ mA}$
	$V_{OH}$	Output Voltage, Logic 1 (3)	$V_{SS} - 1$			V	$I_L = +100 \mu\text{A}$
DYNAMIC CHAR.	$t_{DLH}$	Output Delay, Low to High (3)			450	ns	See Timing Diagram and Test Circuit
	$t_{DHL}$	Output Delay, High to Low (3)			450	ns	
	$t_{VOR}$	Output Voltage Rise Time (3)		100	150	ns	
	$t_{VOF}$	Output Voltage Fall Time (3)		100	150	ns	

### NOTES:

- Other supply voltages are permissible providing that supply and input voltages are adjusted to maintain the same potential relative to  $V_{SS}$ , e.g.,  $V_{SS} = 0\text{V}$ ,  $V_{DD} = -5 \pm 0.25\text{V}$ ,  $V_{GG} = -17 \pm 0.85\text{V}$ .
- MOS pull-up resistors to  $+5\text{V}$  are provided internally. These MOS resistors are enabled by connecting  $VR_A$ ,  $VR_B$  and  $VR_\phi$  to  $V_{GG}$ , and disabled by connecting  $VR_A$ ,  $VR_B$  and  $VR_\phi$  to  $V_{SS}$ . Pull-up resistors not provided at recirculate inputs.
- At  $T_A = 25^\circ\text{C}$ .

## TIMING



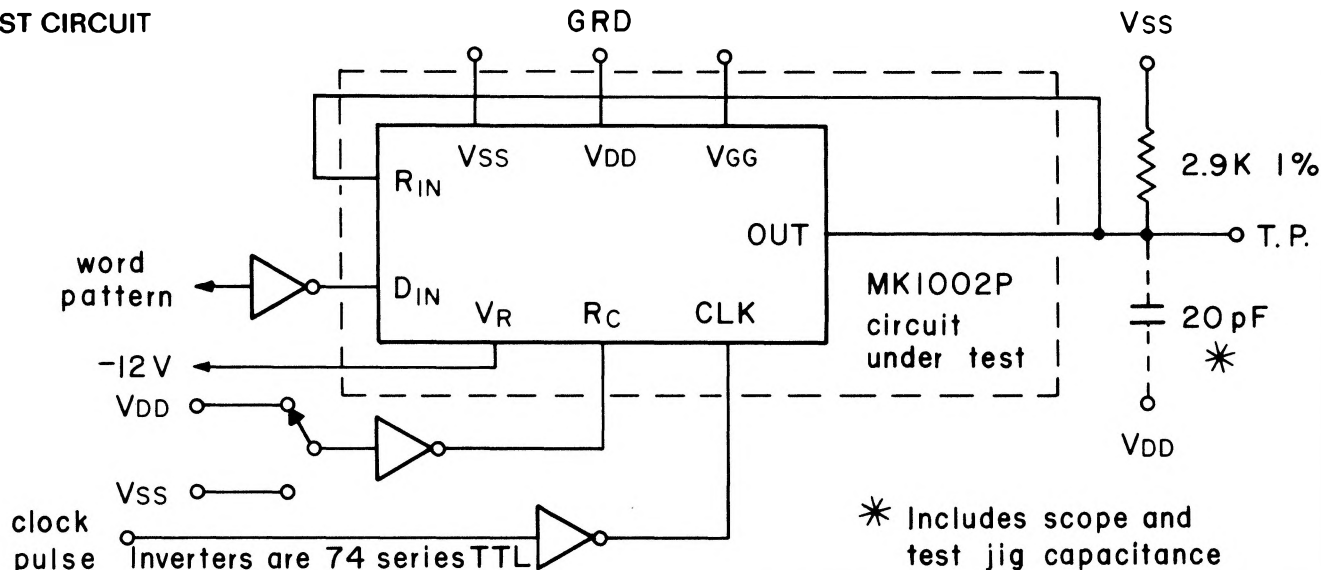
The timing diagram applies to either section of the dual shift register. The test conditions for these waveforms are illustrated below. A logic "1" is defined as +5 V and a logic "0" is defined as 0V

As long as  $R_C$  is at a "1",  $R_{in}$  is disabled and  $D_{in}$  is enabled. The data that is present at  $D_{in}$  while the clock is at "0" is shifted in and will be stored as the clock goes to a "1". This data must have been present  $t_{dld}$  time prior to the clock "1" edge. The data must also remain in that same state for  $t_{dlg}$  time after that edge. These times are necessary to insure proper data storage in the first register-cell.

On the clock "1" edge, data is shifted through the register causing bit 127 to be shifted to position 128. This cell's output is buffered and appears at the output in the same logic polarity that appeared at the input 128 clocks prior. This data appears within  $t_{pd}$  time of the clock "1" edge.

$R_{in}$  may be hardwired to the data output. When  $R_C$  is at a "0",  $R_{in}$  is enabled and  $D_{in}$  is disabled. Therefore, the output data will appear at the input of the first cell. When  $R_{in}$  is tied to the data output, the output delay will insure  $t_{dld}$  and  $t_{dlg}$  times.  $R_C$  "0" time must lead the clock "1" edge by  $t_{rld}$  time and must lag that edge by  $t_{rlg}$  time to insure proper data storage when recirculate storage is desired.

## TEST CIRCUIT



[illegible]

This shows the MK 1002 P connected to operate as a single, 256-bit, static shift register. Pull-up resistors are enabled at TTL driven inputs and disabled at MOS or DTL driven inputs. Any similar TTL/DTL device may be used in place of the inverters shown.

Inverters are 74-series TTL

[illegible]

**TYPICAL PERFORMANCE**

**Left Graph: Power Dissipation ( $P_D$ ) vs. Ambient Temperature ( $T_A$ )**

Y-axis:  $P_D$  (mW) (95 to 140)  
X-axis:  $T_A$  ( $^{\circ}$ C) (0 to 80)

Operating Conditions:  
 $f_{\phi} = 1 \text{ MHz}$   
 $V_{SS} = 5.0 \text{ V}$   
 $V_{DD} = 0.0 \text{ V}$   
 $V_{GG} = -12.0 \text{ V}$

$T_A$ ( $^{\circ}$ C)	$P_D$ (mW)
0	142
10	135
20	128
30	121
40	114
50	107
60	100
70	93
80	86

**Right Graph: Output Delay vs. Ambient Temperature ( $T_A$ )**

Y-axis: OUTPUT DELAY (ns) (0 to 400)  
X-axis:  $T_A$  ( $^{\circ}$ C) (0 to 80)

Operating Conditions:  
 $V_{SS} = 5.0 \text{ V}$   
 $V_{DD} = 0 \text{ V}$   
 $V_{GG} = -12.0 \text{ V}$

$T_A$ ( $^{\circ}$ C)	OUTPUT DELAY (ns)
0	270
10	290
20	310
30	330
40	350
50	370
60	390
70	410
80	430

